IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Akira Ishikawa Art Unit: Unknown Serial No.: New Divisional Application Examiner: Unknown

Filed: December 3, 2003

Title : SEMICONDUCTOR DEVICE AND MANUFACTURING METHOD THEREOF

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Under 35 USC §120, this application relies on the earlier filing date of application serial number 09/951,384, filed on September 14, 2001. The attached list of references were submitted to and/or cited by the Office in the prior application and, therefore, are not provided in this application.

This statement is being filed with the application. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 12/8/03

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Substitute Form PTO-1449 (Modified)	Form PTO-1449 U.S. Department of Commerce Patent and Trademark Office		Application No. New Divisional	
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Akira Ishikawa		
		Filing Date December 3, 2003	Group Art Unit	

			U.S. Pate	ent Documents			
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,376,561	12/27/1994	Vu et al.			04/24/1992
	AB	5,643,826	07/01/1997	Ohtani et al.			10/25/1994
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Foreign Patent Documents or Published Foreign Patent Applications								
Examiner	Desig.	Document	Publication	Country or			Trans	lation
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AN							
·	AO							
	AP							
	AQ							

Other Documents (include Author, Title, Date, and Place of Publication)				
Examiner Initial	Desig. ID	Document		
	AR			
	AS			
	ΑТ			

Examiner Signature	Date Considered				
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with					
next communication to applicant.					